

## **2 Postdoctoral Positions in Scanning Transmission Electron Microscopy (STEM) and Electron Energy Loss Spectroscopy (EELS) at the University Complutense of Madrid (UCM) Spain**

Applicants should have a strong background in materials physics, preferably in magnetism and thin films. Preference will be given to applicants with demonstrated experience in TEM, particularly expertise in STEM techniques, such as electron energy loss spectroscopy and atomic resolution HAADF imaging. Facilities at UCM include a Jeol 3000F TEM-STEM operated at 300 kV and equipped with variable temperature holders. Significant collaboration is foreseen with Oak Ridge National Laboratory (ORNL). Facilities at ORNL include three aberration corrected dedicated STEMs operated at 300 kV (VG Microscopes HB603U) and 100 kV (Nion UltraSTEM and VG Microscopes HB501UX).

Research projects include the characterization of advanced materials by aberration corrected STEM and EELS, such as interfaces in magnetic oxide thin films and superlattices at variable temperatures.

The positions are available in February 2010. Duration about 2 years. Candidates must have a Ph.D. in Physics, Materials Science or Chemistry. A UE citizenship would be valued. Successful applicants are expected to spend extended periods of time at Oak Ridge National Laboratory as well, so they must be available to travel. Candidates interested in learning about application guidelines should send a CV, publication list and the names of three references with their contact information to:

Dr. Maria Varela, Oak Ridge National Laboratory ([mvarela@ornl.gov](mailto:mvarela@ornl.gov))